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L Number	Hits	Search Text	DB	Time stamp
1	9	(("4536608") or ("4554727") or ("4760440") or ("4826267") or ("5151917") or ("5417799") or ("5895233") or	USPAT	2004/08/18 14:53
2	1	("6359735") or ("6384473")).PN. ((("4536608") or ("4554727") or ("4760440") or ("4826267") or ("5151917") or ("5417799") or ("5895233") or ("6359735") or ("6384473")).PN.) and	USPAT	2004/08/18 14:54
3	1	wafer and post\$4 ((("4536608") or ("4554727") or ("4760440") or ("4826267") or ("5151917") or ("5417799") or ("5895233") or ("6359735") or ("6384473")).PN.) and	USPAT	2004/08/18 14:55
4	1	<pre>wafer and post\$4 and cavity ((("4536608") or ("4554727") or ("4760440") or ("4826267") or ("5151917") or ("5417799") or ("5895233") or ("6359735") or ("6384473")).PN.) and</pre>	USPAT	2004/08/18 14:55
5	1	wafer and post\$4 and cavity and etch\$4 ((("4536608") or ("4554727") or ("4760440") or ("4826267") or ("5151917") or ("5417799") or ("5895233") or ("6359735") or ("6384473")).PN.) and wafer and post\$4 and cavity and etch\$4	USPAT	2004/08/18 14:55
7	0	and pattern ((("4536608") or ("4554727") or ("4760440") or ("4826267") or ("5151917") or ("5417799") or ("5895233") or ("6359735") or ("6384473")).PN.) and wafer and post\$4 and cavity and etch\$4	USPAT	2004/08/18 14:55
6	1	and pattern and field and mask ((("4536608") or ("4554727") or ("4760440") or ("4826267") or ("5151917") or ("5417799") or ("5895233") or ("6359735") or ("6384473")).PN.) and wafer and post\$4 and cavity and etch\$4	USPAT	2004/08/18 14:55
8	3	and pattern and field "optical device" and infrared and pattern and field and post\$4 and etch\$4 and antireflection and seal\$4	USPAT	2004/08/18 14:58
-	1	("6627892").PN.	USPAT	2004/08/18 12:11
-	265	438/64.ccls.	USPAT	2004/08/18
-	11	438/64.ccls. and (wafer with mask\$4)	USPAT USPAT	2004/08/18 12:11 2004/08/18
_	2	438/64.ccls. and (wafer with mask\$4)and field and post 438/64.ccls. and (wafer with mask\$4)and	USPAT	12:12 2004/08/18
_	0	field and post and etch\$4 438/64.ccls. and (wafer with mask\$4)and	USPAT	12:12 2004/08/18
-	1	field and post and etch\$4 and cavity 438/64.ccls. and (wafer with mask\$4)and field and post and etch\$4 and (cavity or	USPAT	12:12 2004/08/18 12:12
_	1	trench or via or hole or opening) 438/64.ccls. and (wafer with mask\$4) and field and post and etch\$4 and (cavity or trench or via or hole or opening) and	USPAT	2004/08/18 12:13
-	109	form\$4 438/64.ccls. and optical	USPAT	2004/08/18
-	19	438/64.ccls. and optical and infrared	USPAT	2004/08/18
-	12	wafer		2004/08/18 12:13
-	12	wafer and field	USPAT	2004/08/18
_	1	438/64.ccls. and optical and infrared and wafer and field and post\$4	USPAT	2004/08/18 12:13

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-	0	438/64.ccls. and optical and infrared and	USPAT	2004/08/18
ļ		wafer and field and post\$4 and cavity		12:13
-	5	438/64.ccls. and optical and infrared and	USPAT	2004/08/18
		wafer and field and cavity		12:18
_	10	"infrared optical device"	USPAT	2004/08/18
		<u>-</u>		12:19
_	1	"infrared optical device" and pattern and	USPAT	2004/08/18
		field and post		12:20
-	16478	"optical device"	USPAT	2004/08/18
		•		12:20
_	2975	"optical device" and infrared	USPAT	2004/08/18
		•		12:20
_	224	"optical device" and infrared and pattern	USPAT	2004/08/18
		and field and post\$4		12:21
_	13	"optical device" and infrared and pattern	USPAT	2004/08/18
		and field and post\$4 and etch\$4 and		12:21
		antireflection		
-	1	"optical device" and infrared and pattern	USPAT	2004/08/18
		and field and post\$4 and etch\$4 and		12:22
		antireflection and seal\$4 and bolometer\$4		
_	51		USPAT	2004/08/18
		with wafer)		12:23
-	1	"optical device" and infrared and (mask	USPAT	2004/08/18
		with wafer) and pattern and etch\$4 and		14:52
		post\$4 and cavity		